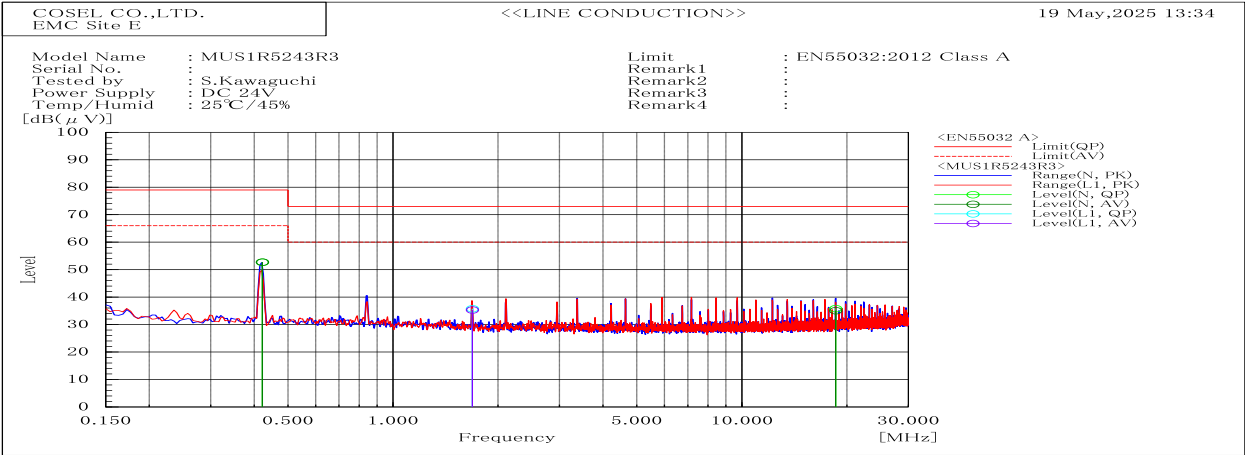
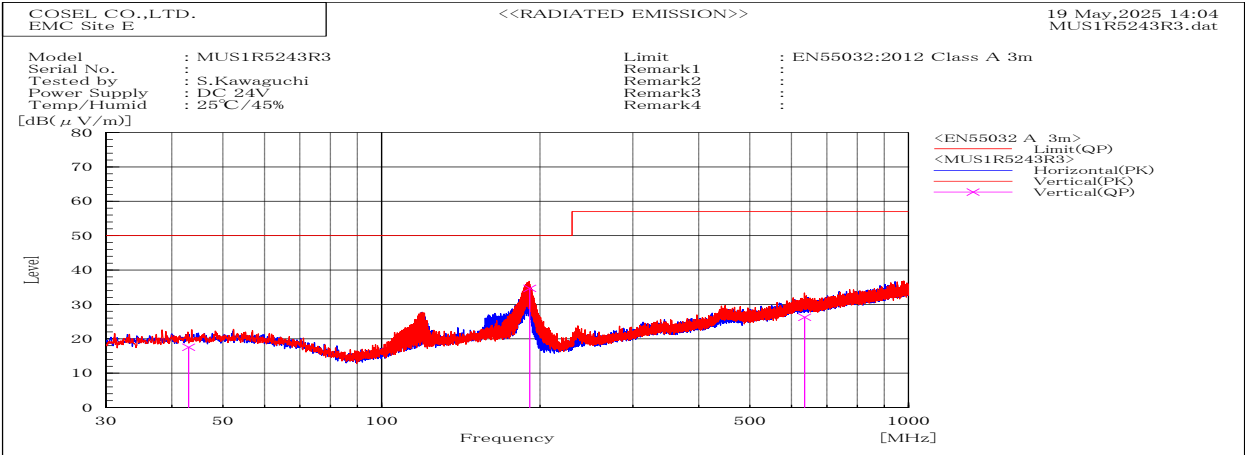


DATA SHEET		Date	19-May-25
Model	MUS1R5243R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi



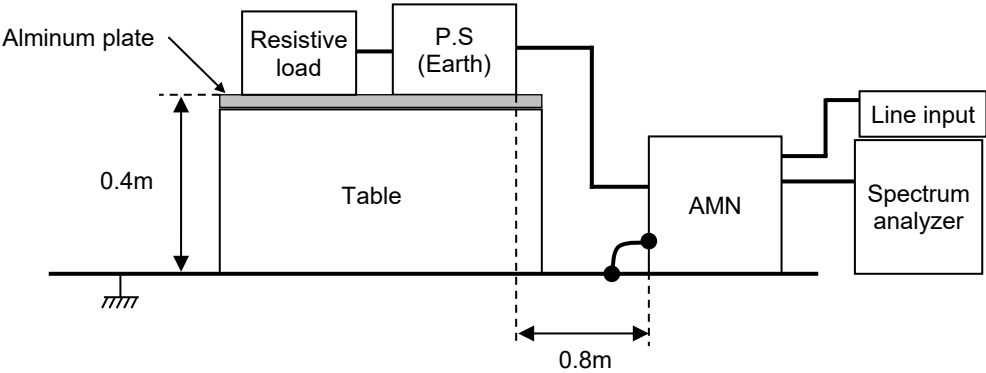
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.422	N	52.7	52.7	79	66	26.3	13.3	Pass	
18.572	N	35.8	35	73	60	37.2	25	Pass	
1.688	L1	35.7	35.3	73	60	37.3	24.7	Pass	



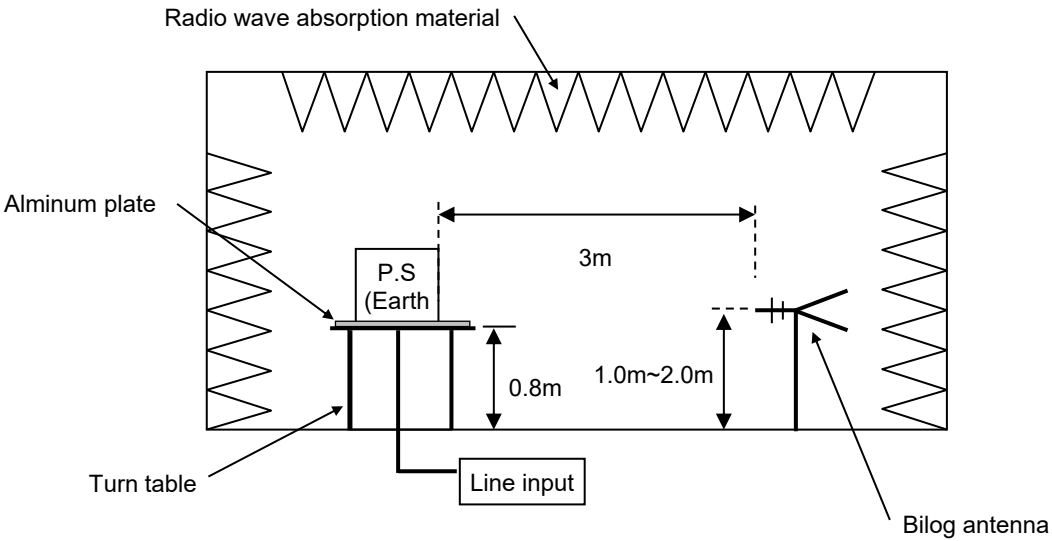
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP					
191.149	V	Stable	34.7	50	15.3	Pass	100.2	6.4	
43.038	V	Stable	17.6	50	32.4	Pass	100	357.2	
635.184	V	Stable	26.3	57	30.7	Pass	200	203.5	

DATA SHEET		Date	19-May-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission

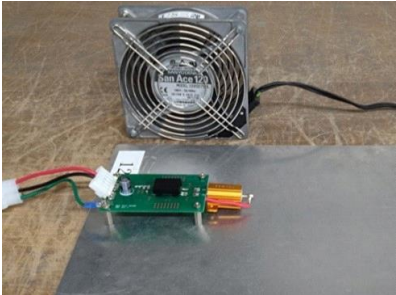


Conditions

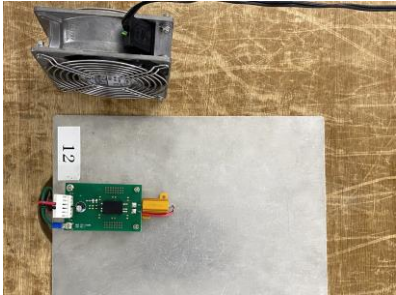
Test : EMI
Model Name: MUS1R5□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

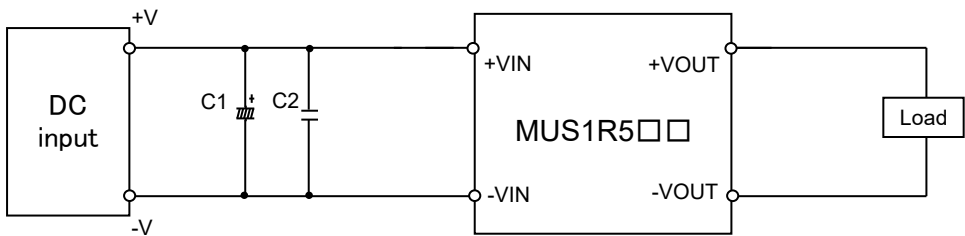


Fig.1 MUS1R505□, MUS1R512□, MUS1R524□ Testing circuitry

- | | | | |
|------|-----------|-----------------|---|
| C1 : | MUS1R505□ | 16V 220 μ F | Electric capacitor (UPWseries NICHICON) |
| | MUS1R512□ | 50V 100 μ F | Electric capacitor (UPWseries NICHICON) |
| | MUS1R524□ | - | |
| C2 : | MUS1R505□ | 16V 22 μ F | Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING) |
| | MUS1R512□ | 25V 22 μ F | Ceramic capacitor (C3216JB1E226MT TDK) |
| | MUS1R524□ | 50V 10 μ F | Ceramic capacitor (C3216X7R1H106KT TDK) |

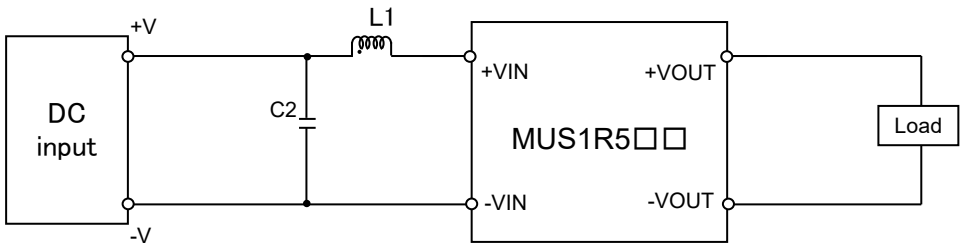


Fig.2 MUS1R548□ Testing circuitry

- | | | | |
|------|-----------|------------------|--|
| C2 : | MUS1R548□ | 100V 2.2 μ F | Ceramic capacitor (C3216X7S2A225KT TDK) |
| L1 : | MUS1R548□ | 520mA 15 μ H | Inductor (LQH32PN150MN0L MURATA MANUFACTURING) |